Charlotte Zborowski

List of Publications by Year
in descending order

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Version: 2024-02-01

16	161	1478280 6	1199470 12
papers	citations	h-index	g-index

16	16	16	136
all docs	docs citations	times ranked	citing authors

#	Article	IF	Citations
1	Improved depth information from routine analysis of the inelastic background of XPS and HAXPES spectra using optimized twoâ€•and threeâ€parameter crossâ€sections. Surface and Interface Analysis, 2022, 54, 433-441.	0.8	2
2	Comparison and complementarity of QUASES-Tougaard and SESSA software. Applied Surface Science, 2022, 585, 152758.	3.1	3
3	High-energy x-ray photoelectron spectroscopy spectra of InP measured by Cr KÎ±. Surface Science Spectra, 2022, 29, 014018.	0.3	1
4	High-energy x-ray photoelectron spectroscopy spectra of TiO2 measured by Cr KÎ±. Surface Science Spectra, 2022, 29, 014017.	0.3	2
5	High-energy x-ray photoelectron spectroscopy spectra of Al2O3 measured by Cr KÎ±. Surface Science Spectra, 2022, 29, 014021.	0.3	1
6	High-energy x-ray photoelectron spectroscopy spectra of HfO2 measured by Cr KÎ±. Surface Science Spectra, 2022, 29, 014019.	0.3	1
7	High-energy x-ray photoelectron spectroscopy spectra of TiN measured by Cr KÎ±. Surface Science Spectra, 2022, 29, 014016.	0.3	1
8	Adsorptive behavior of phosphorus onto recycled waste biosolids after being acid leached from wastewater sludge. Chemical Engineering Journal Advances, 2022, 11, 100329.	2.4	3
9	HAXPES of GaN film on Si with Cr KÎ± photons. Surface Science Spectra, 2021, 28, 014006.	0.3	1
10	Surface analysis in the semiconductor industry: Present use and future possibilities. Surface and Interface Analysis, 2020, 52, 786-791.	0.8	4
11	Theoretical study toward rationalizing inelastic background analysis of buried layers in <scp>XPS</scp> and <scp>HAXPES</scp>. Surface and Interface Analysis, 2019, 51, 857-873.	0.8	23
12	Determination of the input parameters for inelastic background analysis combined with HAXPES using a reference sample. Applied Surface Science, 2018, 432, 60-70.	3.1	24
13	Quantitative determination of elemental diffusion from deeply buried layers by photoelectron spectroscopy. Journal of Applied Physics, 2018, 124, .	1.1	22
14	Analysis of buried interfaces in multilayer device structures with hard XPS (HAXPES) using a CrKÎ± source. Surface and Interface Analysis, 2018, 50, 1158-1162.	0.8	23
15	Effective inelastic scattering cross-sections for background analysis in HAXPES of deeply buried layers. Applied Surface Science, 2017, 402, 78-85.	3.1	33
16	Quantitative spectromicroscopy from inelastically scattered photoelectrons in the hard X-ray range. Applied Physics Letters, 2016, 109, .	1.5	17